

## Transaction Information

Tool ID	KF06
Tool Status	Connected
Location	East Fishkill, USA
Wafer Size	300 mm
Fab Section	Metrology
Tool Available Date	2021-01-22

## General Product Information

Vendor Supplier	NANOMETRIC
Model	Caliper
Vintage	2003
Serial No	QS-2265
Asset Description	Accent Calipar elan Overlay Inspection Tool
Software Version	Standard
CIM	SECS, GEM
Process	Overlay Inspection

## Hardware Configuration (Fab)

System Type	Description	Quantity	Status
Main System	Overlay Inspection Units	1	OK
Handler System	Brooks	1	OK
Factory Interface	FOUP	2	OK
Options System	N/A		
Others	N/A		

## Hardware Configuration (Subfab / Auxilliary Units)

Description	Quantity	Status
None		

## Missing/Faulty Parts / Accesories List

Description	Quantity
Missing stage controller card	1

# Tool Pictures

General

Main Tool



Manufacture Serial

Serial Plate



## Additional Configuration Files